

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Walter SCHWARZENBACH et al.

Confirmation No.:

Application No.: 10/766,207

Group Art Unit:

Filing Date: January 29, 2004

Examiner:

For: METHOD FOR DETACHING A LAYER
FROM A WAFER USING A LOCALIZED
STARTING AREA

Attorney Docket No.: 4717-11600

INFORMATION DISCLOSURE STATEMENT

Mail Stop Patent Application

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:


Pursuant to Applicants' duty of disclosure under 37 C.F.R. §1.56, enclosed is a Form PTO-1449 on which six (6) references are listed for the Examiner's review and consideration. The references were cited in the Search Report for the priority French application, and a copy of the Search Report is enclosed. Copies of non-U.S. patent references AD – AF are submitted herewith. Copies of U.S. patent references AA – AC will be provided if the Examiner so requests. It is respectfully requested that the references be made of record in this application by the Examiner's completion and return of Form PTO-1449.

This Information Disclosure Statement is filed under 37 C.F.R. §1.97(b)(3), before the mailing of a first Office Action on the merits. Thus, no fee is believed to be due. Should any fees be required, however, please charge such fees to Winston & Strawn LLP Deposit Account No. 50-1814.

Respectfully submitted,

April 27, 2004

Date


E. Bradley Gould
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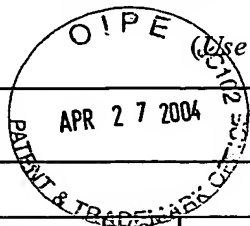
(Reg. No. 30,256)

WINSTON & STRAWN LLP

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202-371-5771

LIST OF REFERENCES CITED BY APPLICANT Form PTO-1449 <i>(Use several sheets if necessary)</i>	ATTY. DOCKET NO.: 4717-11600	APPLICATION NO.: 10/766,207
Sheet 1 of 1	APPLICANT: Walter SCHWARZENBACH et al.	
	FILING DATE: January 29, 2004	GROUP:



U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	CITE NO.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	2003/0087503	05/2003	Sakaguchi et al.			
	AB	6,597,039	07/2003	Ohmi et al.			
	AC	2003/0234075	12/2003	Aspar et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AD	EP 0793263	09/1997	Europe				
	AE	EP 0938129	08/1999	Europe				
	AF	WO 02/05344	01/2002	PCT				

OTHER REFERENCES *(Including Author, Title, Date, Pertinent Pages, Etc.)*

EXAMINER	DATE CONSIDERED
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.